Search Notes



Appli	cation	/Cont	ro	ı	N	0.

10/811,518 Examiner

Felix J. Nepveux

Applicant(s)/Patent under Reexamination

HEER ET AL.

Art Unit

1617

SEARCHED			
Class	Subclass	Date	Examiner
424	405	8/7/2005	F
514	241	8/7/2005	AN

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH N (INCLUDING SEARC		')
	DATE	EXMR
Structure Search	8/1/2005	For
Inventor Search .	8/7/2005	For
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